

### **IGBT3 Power Chip**

### Features:

- 1700V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

### This chip is used for:

• power modules

### Applications:

drives



Chip Type	<b>V</b> <sub>CE</sub>	<i>I</i> <sub>C</sub>	Die Size	Package
SIGC128T170R3E	1700V	100A	11.33 x 11.33 mm <sup>2</sup>	sawn on foil

### **Mechanical Parameters**

Wechanical Farameters			
Raster size	11.33 x 11.33		
Emitter pad size (incl. gate pad)	8 x ( 4.48 x 2.15 )	mm²	
Gate pad size	1.303 x 0.838		
Area total	128.4		
Thickness	190	μm	
Wafer size	200	mm	
Max.possible chips per wafer	198		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500μm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



### **Maximum Ratings**

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, $T_{vj}$ =25 °C	V <sub>CE</sub>	1700	V	
DC collector current, limited by $T_{\rm vj\;max}$	I <sub>C</sub>	1)	А	
Pulsed collector current, $t_p$ limited by $T_{vj max}$	$I_{c,puls}$	300	Α	
Gate emitter voltage	V <sub>GE</sub>	±20	V	
Junction temperature range	T <sub>vj</sub>	-40 +175	°C	
Operating junction temperature	$T_{\rm vj}$	-40+150	°C	
Short circuit data <sup>2)</sup> $V_{GE} = 15V$ , $V_{CC} = 1000V$ , $T_{vj} = 150$ °C	$t_{SC}$	10	μs	
Reverse bias safe operating area <sup>2)</sup> (RBSOA)	$I_{C,max} = 200A, V_{CE,max} = 1700V$ $T_{vj} \le 150^{\circ}C$			

<sup>1)</sup> depending on thermal properties of assembly

### **Static Characteristic** (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter		Conditions	min.	typ.	max.	0.111
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 3.5 mA	1700			
Collector-Emitter saturation voltage	V <sub>CEsat</sub> <sup>3)</sup>	V <sub>GE</sub> =15V, I <sub>C</sub> =100A	1.6	2	2.4	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =4mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1700V , V <sub>GE</sub> =0V			5.6	μA
Gate-Emitter leakage current	I <sub>GES</sub>	$V_{\text{CE}}$ =0V , $V_{\text{GE}}$ =20V			600	nA
Integrated gate resistor	$r_{\rm G}$			7.5		Ω

<sup>3)</sup> Vcesat tested at lower current

### **Dynamic Characteristic** (not subject to production test - verified by design / characterization), $T_{vj}$ =25 °C

Parameter	Cymbal	Conditions	Value			Unit
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Cies	$V_{CE}=25V$ , $V_{GE}=0V$ , f=1MHz		8815		
Reverse transfer capacitance	C <sub>res</sub>			292		pF

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterization

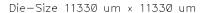


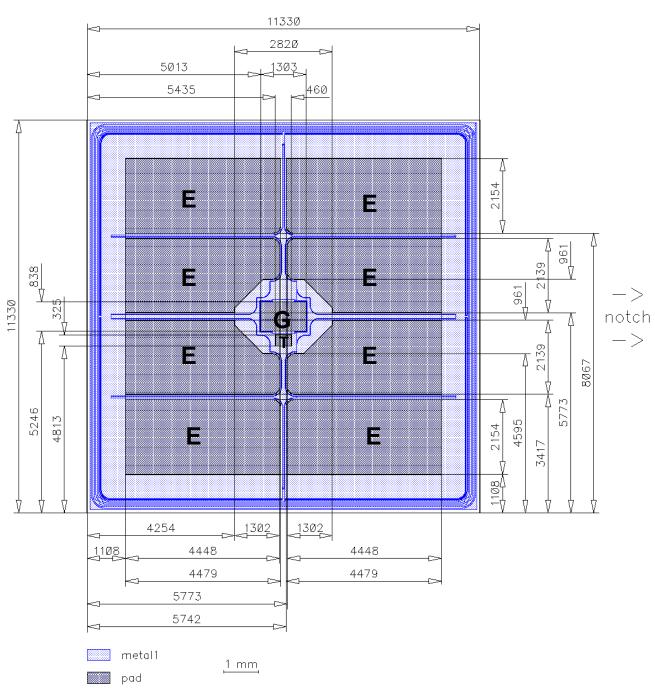
### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



### **Chip Drawing**





**E** = Emitter

**G** = Gate

**T** = Test pad do not contact



#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date
2.1	Change wafer size to 200 mm	14.04.2010
2.2	Additional basic types L7787M, L7787T, L7787E; new gate pad design	01.07.2014

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